

Notice of References Cited	Application/Control No. 10/564,102		Applicant(s)/Patent Under Reexamination KLETTKE ET AL.	
	Examiner Tae H. Yoon		Art Unit 1796	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,894,144	05-2005	Zech et al.	528/394
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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